

# High speed saturated switch

## ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Characteristic and test conditions	Min.	Typ.	Max.	Unit
$h_{FE}$	DC Current Gain (5) $I_C = 10 \text{ mA}$ $V_{CE} = 0.35\text{V}$ $I_C = 10 \text{ mA}$ $V_{CE} = 1\text{V}$ $I_C = 30 \text{ mA}$ $V_{CE} = 1\text{V}$ $I_C = 100 \text{ mA}$ $V_{CE} = 1\text{V}$	35	55		
$V_{BE\ sat}$	Base Saturation Voltage (5) $I_C = 10 \text{ mA}$ $I_B = 1 \text{ mA}$ $I_C = 30 \text{ mA}$ $I_B = 3 \text{ mA}$ $I_C = 100 \text{ mA}$ $I_B = 10 \text{ mA}$	0.7	0.77	0.85	V
$V_{CE\ sat}$	Collector Saturation Voltage (5) $I_C = 10 \text{ mA}$ $I_B = 1 \text{ mA}$ $I_C = 30 \text{ mA}$ $I_B = 3 \text{ mA}$ $I_C = 100 \text{ mA}$ $I_B = 10 \text{ mA}$		0.14 0.17 0.30	0.20 0.25 0.80	V
$i_{CES}$	Collector Reverse Current $V_{CE} = 15$ $V_{EB} = 0$		5	200	nA
$i_{CES(125^\circ\text{C})}$	Collector Reverse Current $V_{CE} = 15\text{V}$ $V_{EB} = 0$		2	70	$\mu\text{A}$
$BV_{CES}$	Collector to Emitter Breakdown Voltage $I_E = 10 \mu\text{A}$ $V_{EB} = 0$	25			V
$BV_{EBO}$	Emitter to Base Breakdown Voltage $I_E = 10 \mu\text{A}$ $I_C = 0$	5			V
$LV_{CER}$	Collector to Emitter Sustaining Voltage (4 and 5) $I_C = 10 \text{ mA}$ $R_{BE} = 10\Omega$	15			V
$LV_{CEO}$	Collector to Emitter Sustaining Voltage (4 and 5) $I_C = 10 \text{ mA}$ $I_B = 0$	10			V
$h_{fe}$	High Freq. Current Gain ( $f=100 \text{ MHz}$ ) $I_C = 10 \text{ mA}$ $V_{CE} = 10\text{V}$	4	6		
$C_{TE}$	Emitter Transition Capacitance $I_E = 0$ $V_{EB} = 0.5\text{V}$	3.7	6		pF
$C_{Cbo}$	Base Collector Capacitance $I_E = 0$ $V_{CB} = 5\text{V}$	2	4		pF
$\tau_a$	Charge Storage Time Constant $I_C \sim I_B1 \sim I_B2 \sim 10 \text{ mA}$		13		ns
$t_{on}$	Turn On Time $I_C \sim 10 \text{ mA}$ $I_B1 \sim 3 \text{ mA}$		12		ns
$t_{off}$	Turn Off Time $I_C \sim 10 \text{ mA}$ $I_B2 \sim 3 \text{ mA}$ $I_B2 \sim 1.5 \text{ mA}$		18		ns

## NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of  $200^\circ\text{C}$  and junction-to-case thermal resistance of  $175^\circ\text{C}/\text{W}$  (derating factor of  $5.7\text{mW}/^\circ\text{C}$ ); junction-to-ambient thermal resistance of  $480^\circ\text{C}/\text{W}$  (derating factor of  $2.1\text{mW}/^\circ\text{C}$ ).
- These ratings refer to a high - current point where collector - to - emitter voltage is lowest. For more information send for SGS - AR 5.
- Measured under pulse conditions: pulse length =  $300 \mu\text{sec}$ ; duty cycle = 1%.

The BSV 89 is an NPN planar epitaxial transistor designed specifically for high - speed saturated switching applications.

## ABSOLUTE MAXIMUM RATINGS (1) ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

**Voltages**

Collector to Emitter (4)	$V_{CEO}$	10 V
Collector to Emitter ( $R_{BE} \leq 10\Omega$ ) (4)	$V_{CER}$	15 V
Collector to Emitter	$V_{CES}$	25 V
Emitter to Base	$V_{EBO}$	5 V

**Temperatures**

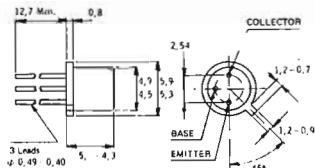
Storage Temperature	$T_{STG}$	-55 $^\circ\text{C}$ to 200 $^\circ\text{C}$
Junction Temperature	$T_J$	200 $^\circ\text{C}$
Lead Temperature (Soldering 10 sec.)	$T_L$	260 $^\circ\text{C}$

**Power (2 - 3)**

Dissipation at 25 $^\circ\text{C}$	$P_D$	1 W
Case Temperature		
Dissipation at 25 $^\circ\text{C}$	$P_D$	0.36 W
Ambient Temperature		

**PHYSICAL DIMENSIONS**

Similar to Jedece TO-8



Note: All dimensions are in mm